



Diagnostic Techniques of Laser-Driven Beams

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Deadline for manuscript
submissions:

closed (31 December 2021)

Message from the Guest Editors

The main goal of the Special Issue on “Diagnostic Techniques for Laser-Plasma produced Radiation” is to present a comprehensive collection of the most recent achievements in the research and development of novel diagnostic devices and techniques for characterization laser-plasma secondary sources. The Issue will be organized into two main sections: i) review papers focused on state-of-the-art detectors, and diagnostic methods for a given source and/or field of application; ii) original research contributions on novel diagnostics for laser-driven secondary sources and their multidisciplinary applications.

Keywords

- X- and gamma-ray diagnostics
- electron beam diagnostics
- ion beam diagnostics
- neutron diagnostics
- diagnostic for optical plasma probing
- EMP characterization and signal contamination
- dosimetry of laser-driven radiation
- detector simulations
- detector calibrations
- radiation damage and hardness
- electronic front-end and control system of pulsed beams
- engineering challenges for laser plasma radiation detection





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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